

Docket No.: N9460.0020/P020
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Eiko Nakazawa, et al.

Application No.: Not Yet Assigned

Filed: Concurrently Herewith

Art Unit: N/A

For: SAMPLE OBSERVATION METHOD AND
TRANSMISSION ELECTRON
MICROSCOPE

Examiner: Not Yet Assigned

CLAIM FOR PRIORITY

MS Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Applicant hereby claims priority under 35 U.S.C. 119 based on the following
prior foreign application filed in the following foreign country on the date indicated:

| <u>Country</u> | <u>Application No.</u> | <u>Date</u> |
|----------------|------------------------|-------------------|
| Japan | 2002-343776 | November 27, 2002 |

Application No.: Not Yet Assigned

Docket No.: N9460.0020/P020

In support of this claim, a certified copy of the said original foreign application will be filed shortly.

Dated: November 25, 2003

Respectfully submitted,

By 

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